

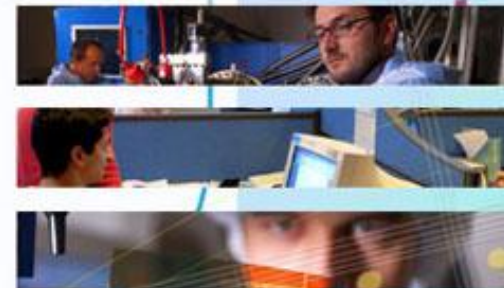
micro and nanoelectronics  
microsystems  
ambient intelligence  
image chain  
biology and health



# Si-based electronics

**M. Brillouët**

**leti**



# Outline

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- Introduction
- Traditional scaling  
never say “impossible”
- Equivalent scaling  
the challenge of the introduction of new concepts
- Alternative concepts  
hypes and reality
- The economical challenge  
it is not rocket science, but...
- Design – technology interaction  
wishful thinking or real need?
- More-than-Moore  
the next frontier?
- Conclusion

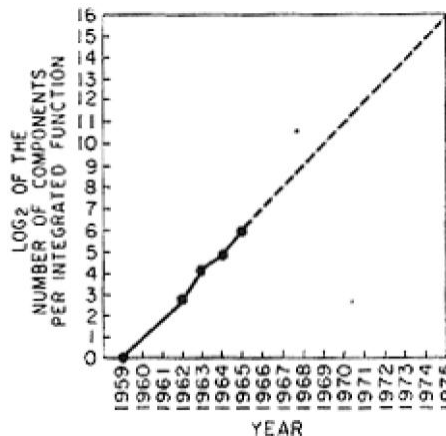
# What Gordon Moore actually said?



G. Moore - 1975

## Higher integration density

nologies were first investigated in the late 1950's. The object was to **miniaturize** electronics equipment **to include increasingly complex electronic functions in limited space** with minimum weight. Several approaches evolved, including



## Digital revolution

Integration will not change linear systems as radically as **digital** systems. Still, a considerable degree of integration

**no reference to  
performance increase**

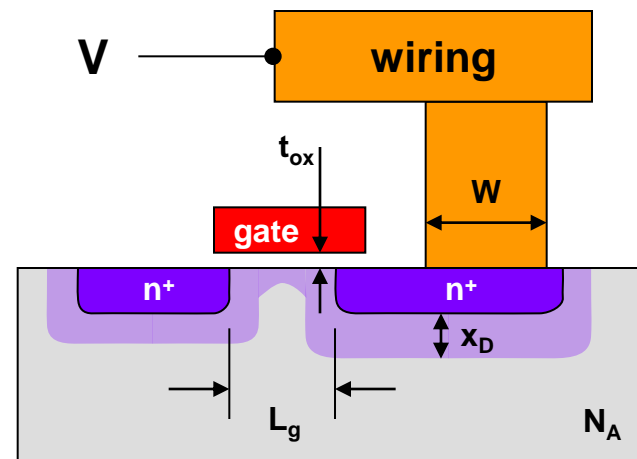
from G. Moore Electronics Vol.38 (8) April 19, 1965

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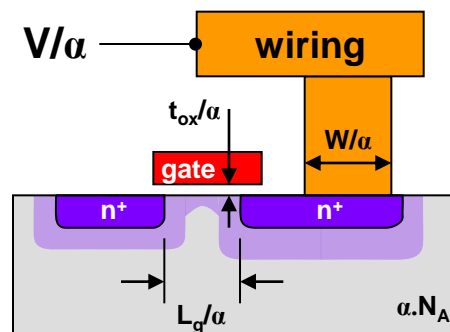
# The happy scaling



R. Dennard © IEEE



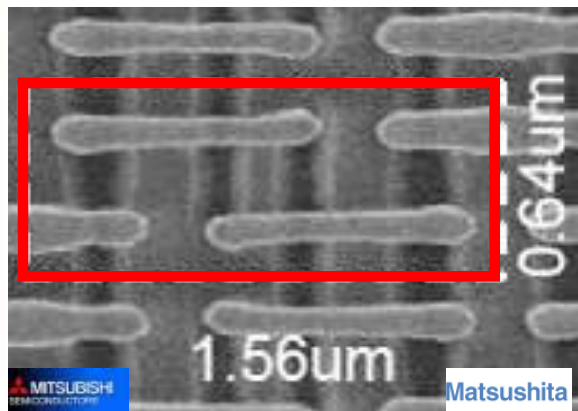
dimensions $t_{ox}$ , $L$ , $W$	$1/\alpha$
doping	$\alpha$
voltage	$1/\alpha$
integration density	$\alpha^2$
delay	$1/\alpha$
power dissipation/Tr	$1/\alpha^2$



# Traditional scaling

Never say “impossible”

# Scaling is a reality

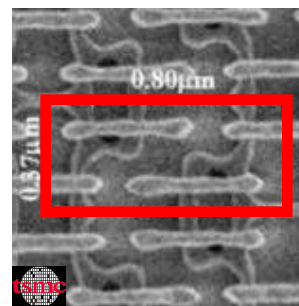


*K. Tomita et al.*  
VLSI 2002 #2.2  
 $0.998\mu\text{m}^2$

90nm



**3x**



*F.L. Yang et al.*  
VLSI 2004 #2.1  
 $0.296\mu\text{m}^2$

45nm



**3x**

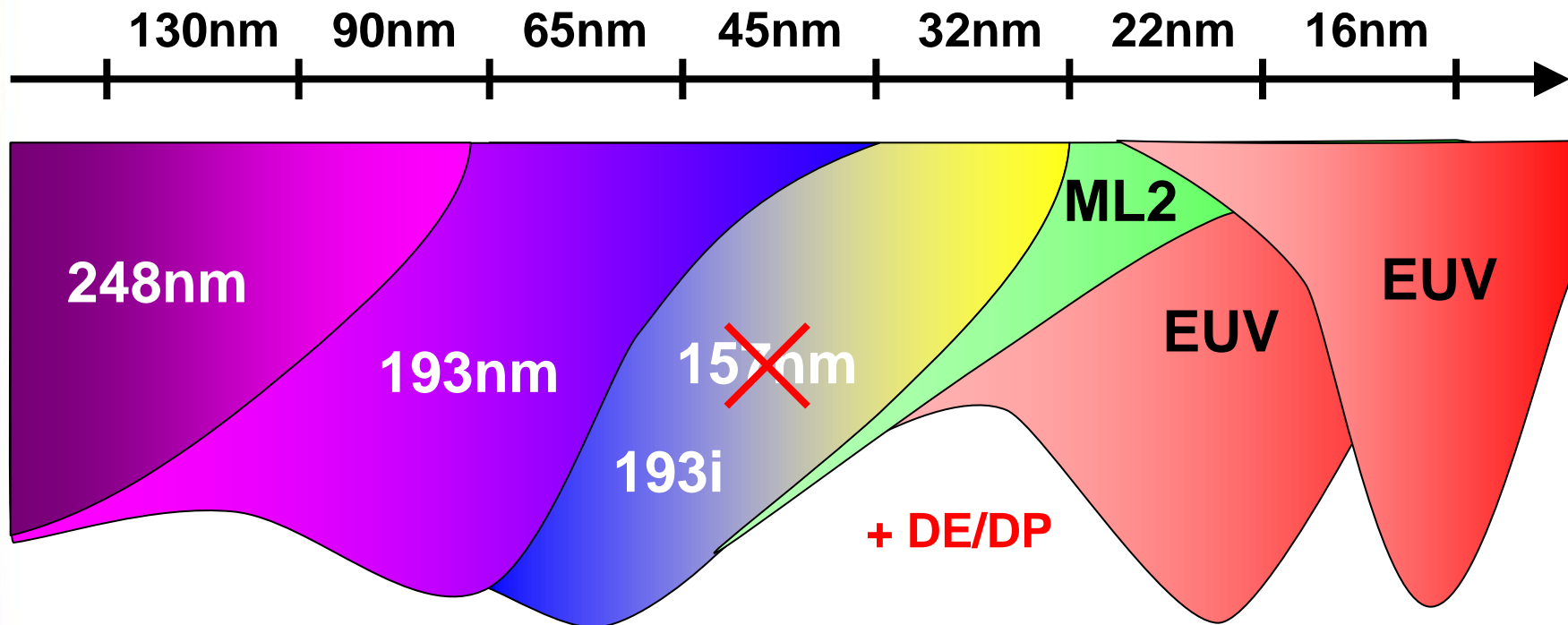


*B.S.Haram et al.*  
IEDM 2008, #27.1  
 $0.100\mu\text{m}^2$

22nm



# Lithography: a key enabler



from



Strategic Research Agenda

disruptive technologies?



ML2

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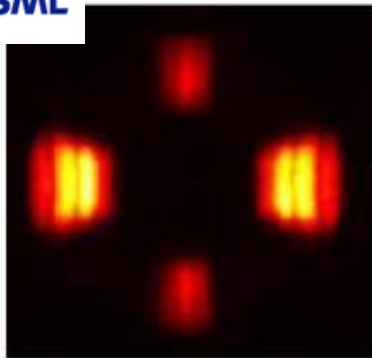
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# Resolution Enhancement Techniques

$$R = k_1 \cdot \frac{\lambda}{NA}$$

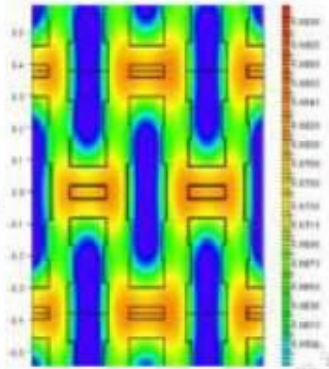
**RET** illumination  
phase  
process

ASML



Exposing  
Illumination

+

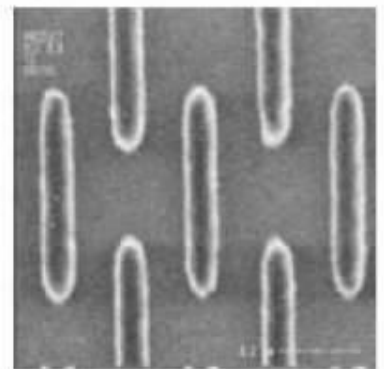


Mask Feature

→ **cost of masks**



=



Top down SEM of  
Resultant Photoresist  
Structure

*de Kim et al., SPIE 2005 & D.Flagello Albany Symposium 2005*

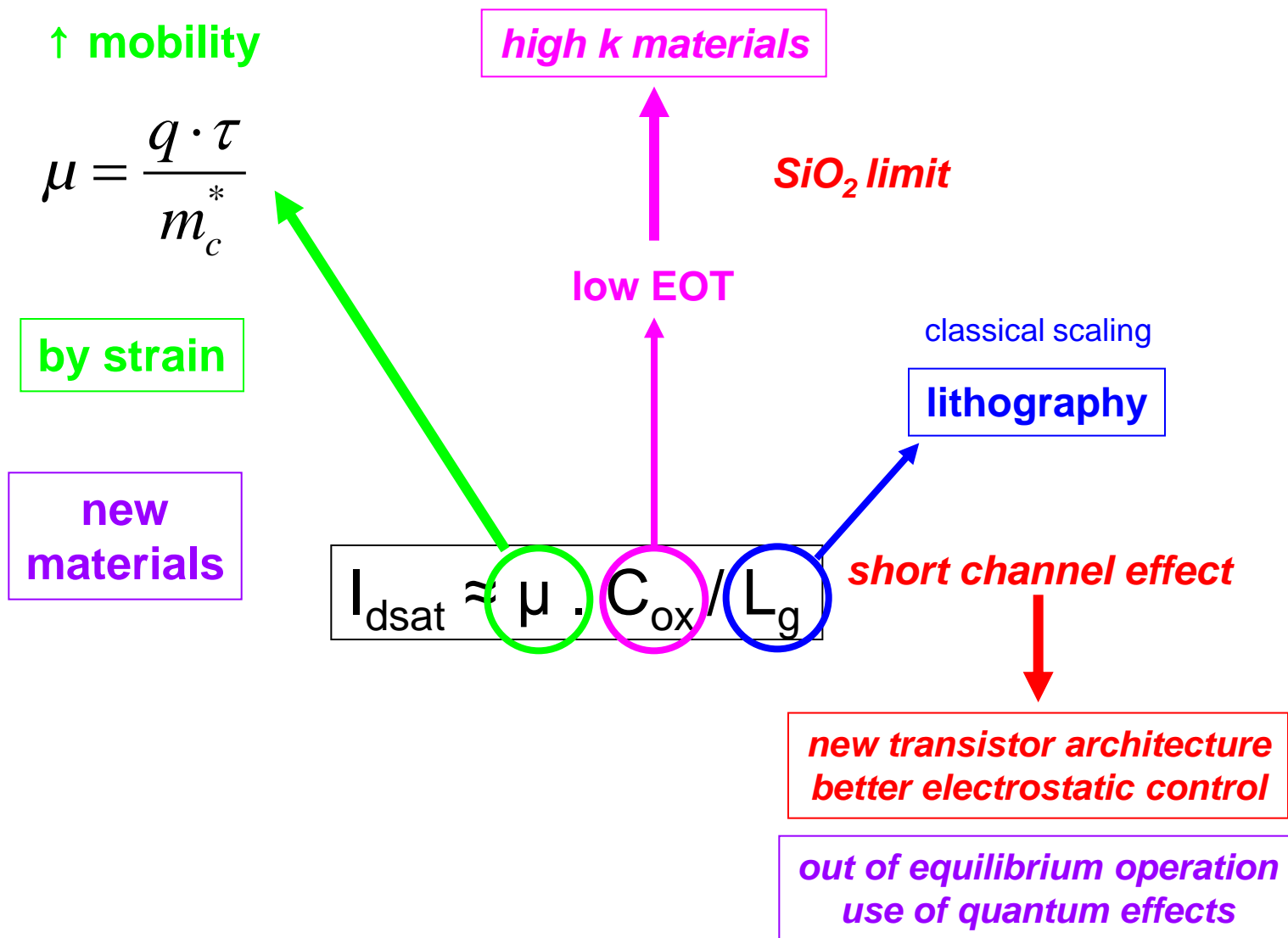
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# Equivalent scaling

The challenge of the introduction of new concepts

# Equivalent scaling



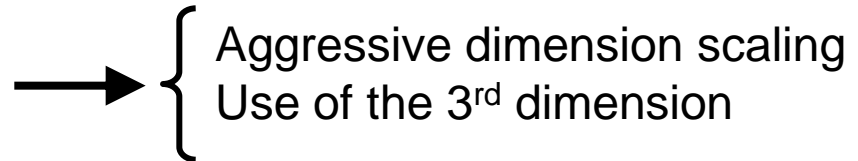
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# What drives memory technologies?

Memory cell = multiple stable & noise immune states  
which can be modified & read from outside

## What drives the progress?

#1. Integration density



#2. Consumption (read, write & stand-by)



#2. Speed

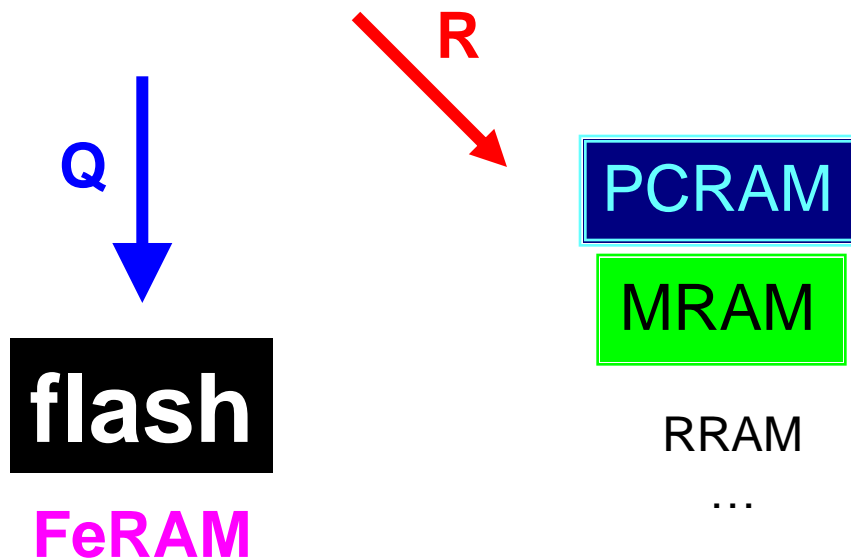
#2. Non-volatility

#3. Correction of a defective information storage

# The “universal” memory

Dense → **DRAM**  
Fast → **SRAM**  
Non volatile → **NAND, NOR**

‘Scalable’  
Low power  
Reliable



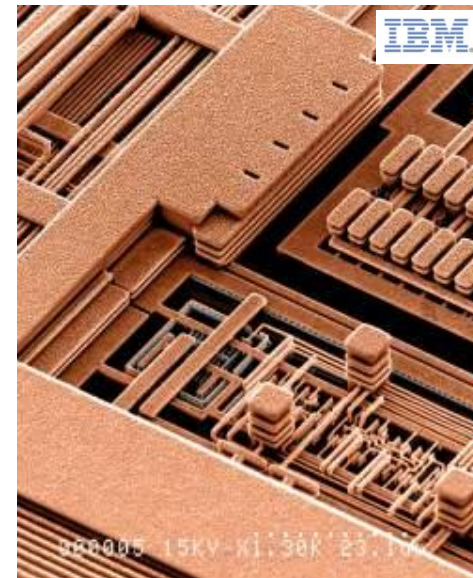
# Interconnection: a major challenge



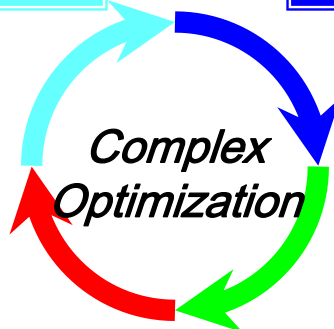
Connectivity



Density

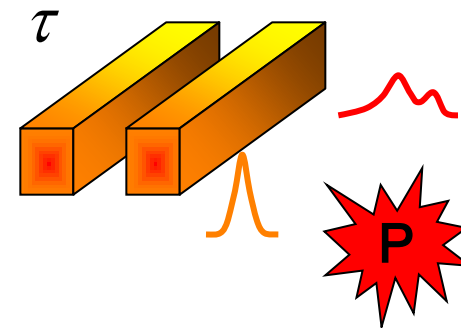


Reliability

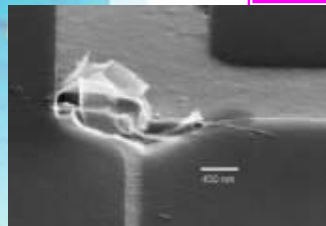
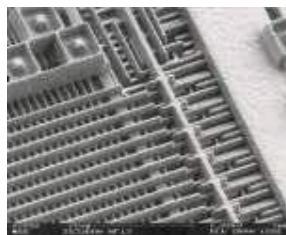


Performance

*Signal integrity*



Yield & cost



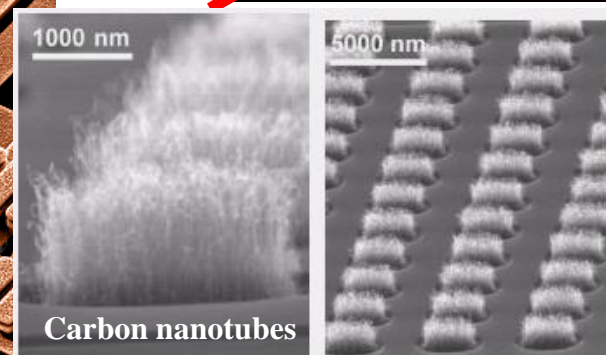
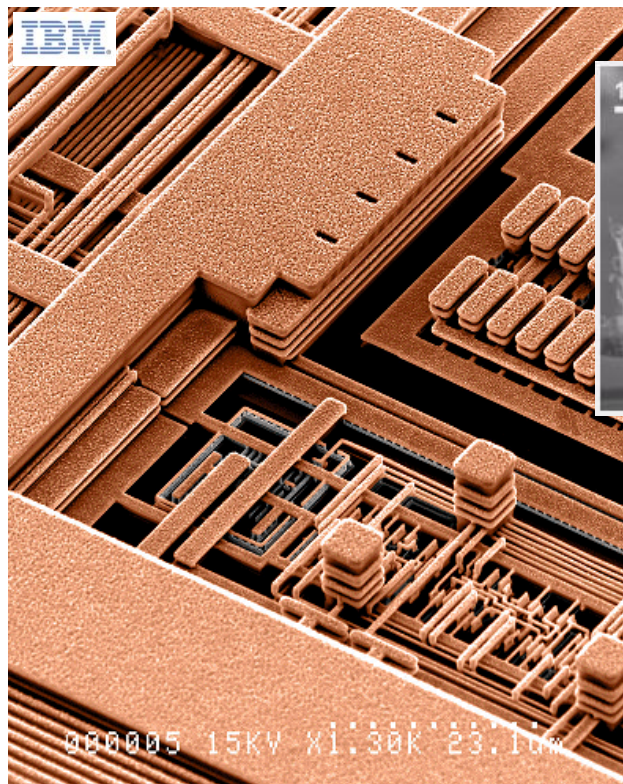
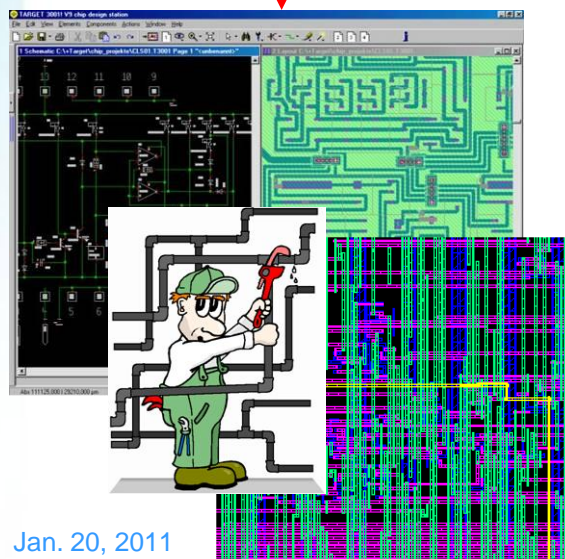
from H. Wendrock et al., ME 82 660 (2005)

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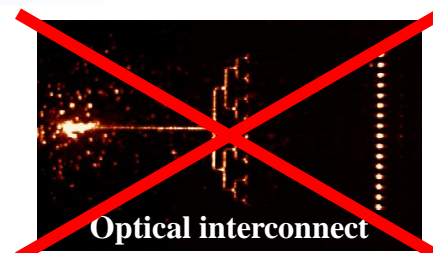


# Interconnection in the short term

Don't dream any **technological** breakthrough



from S.Sato et al. IITC 2006 Paper #12.4



Optical interconnect

Find **design** & manufacturing solutions!

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# Alternative concepts

Hypes and reality

# Physical limits?

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“I am not convinced that there is any such thing as an  
**“ultimate” limit.**

In fact, finding ways to surmount those obstacles  
that, at the present, seem to be the limits  
is what technology is all about”

*R.W. Keyes, IEEE Spectrum, vol. 6, pp.36-45 (1969)*

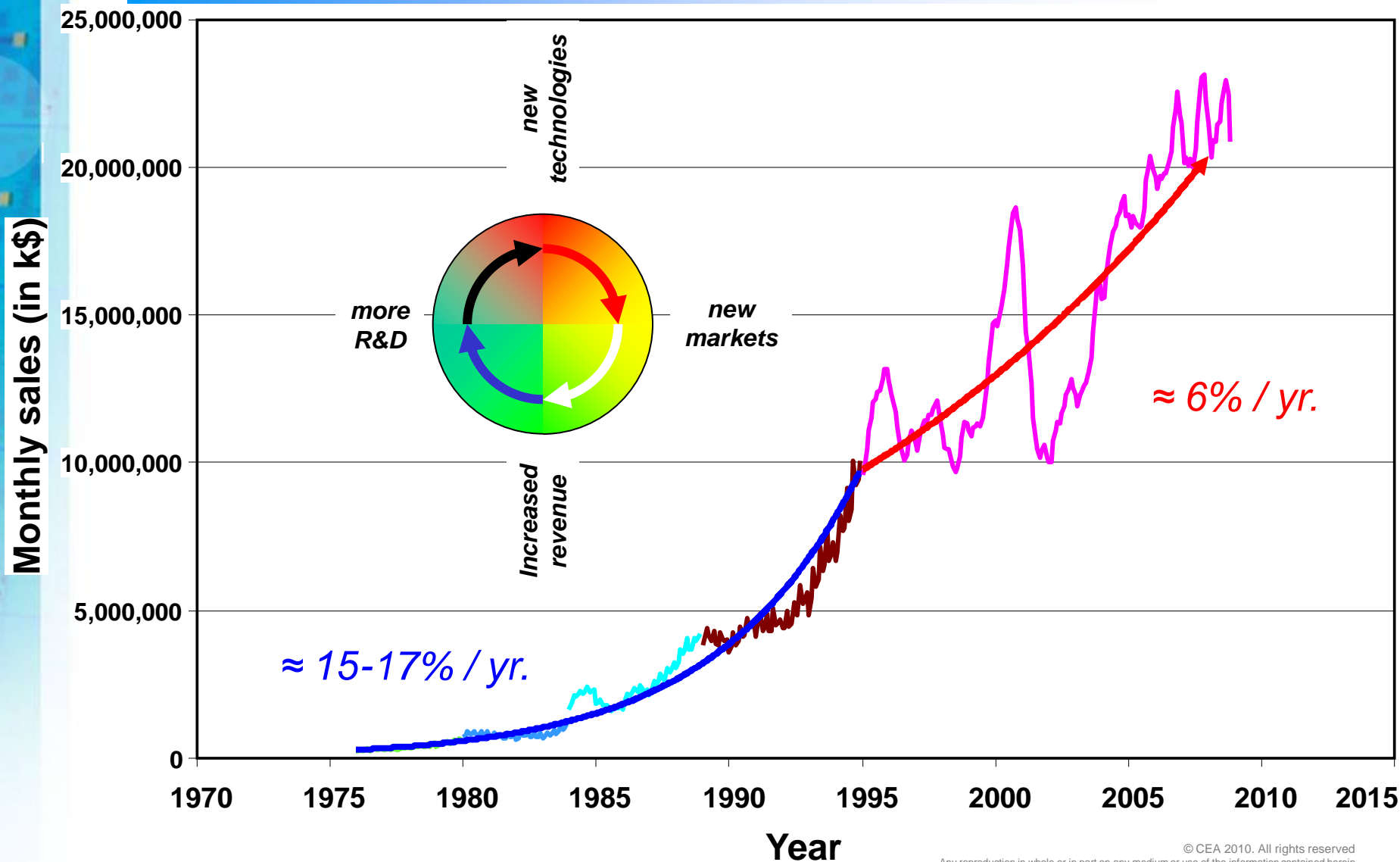
# Some examples

- RTD (resonant tunneling diodes) ['80s]
  - said to allow multi-valued logic
  - sensitive to thicknesses (tunnel effect!)
  - never achieved high complexity circuits
  - it was better to wait for the next CMOS node
- SET (single electron transistor) [90's]
  - the “ultimate” charge-based device
  - room temperature operation challenging
  - CD is critical
  - sensitive to background charges (?)
  - convincing demonstration only on “specialty” devices of lesser complexity (e.g. noise generation)

# The economical challenge

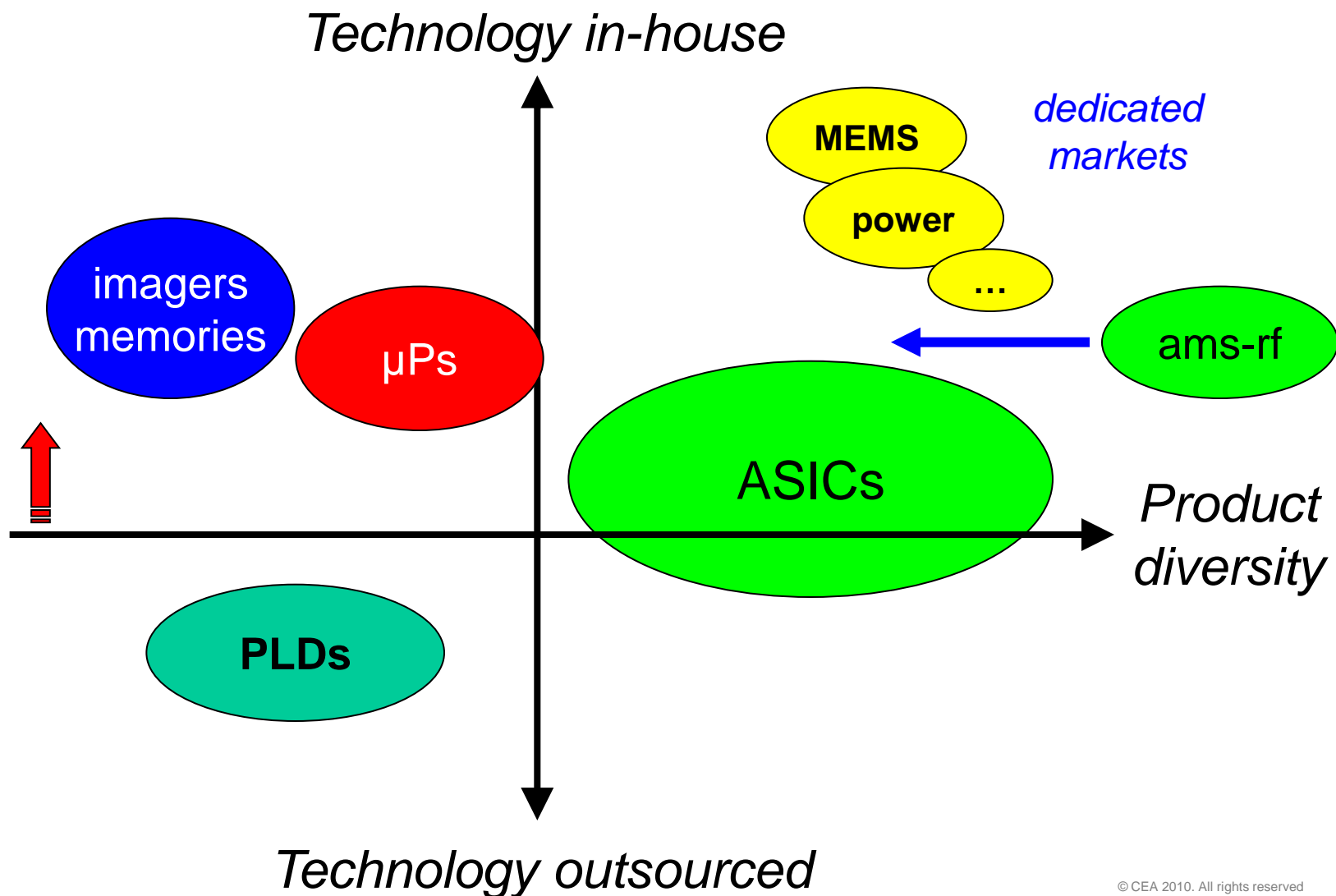
It is not rocket science, but...

# The microelectronic virtuous circle



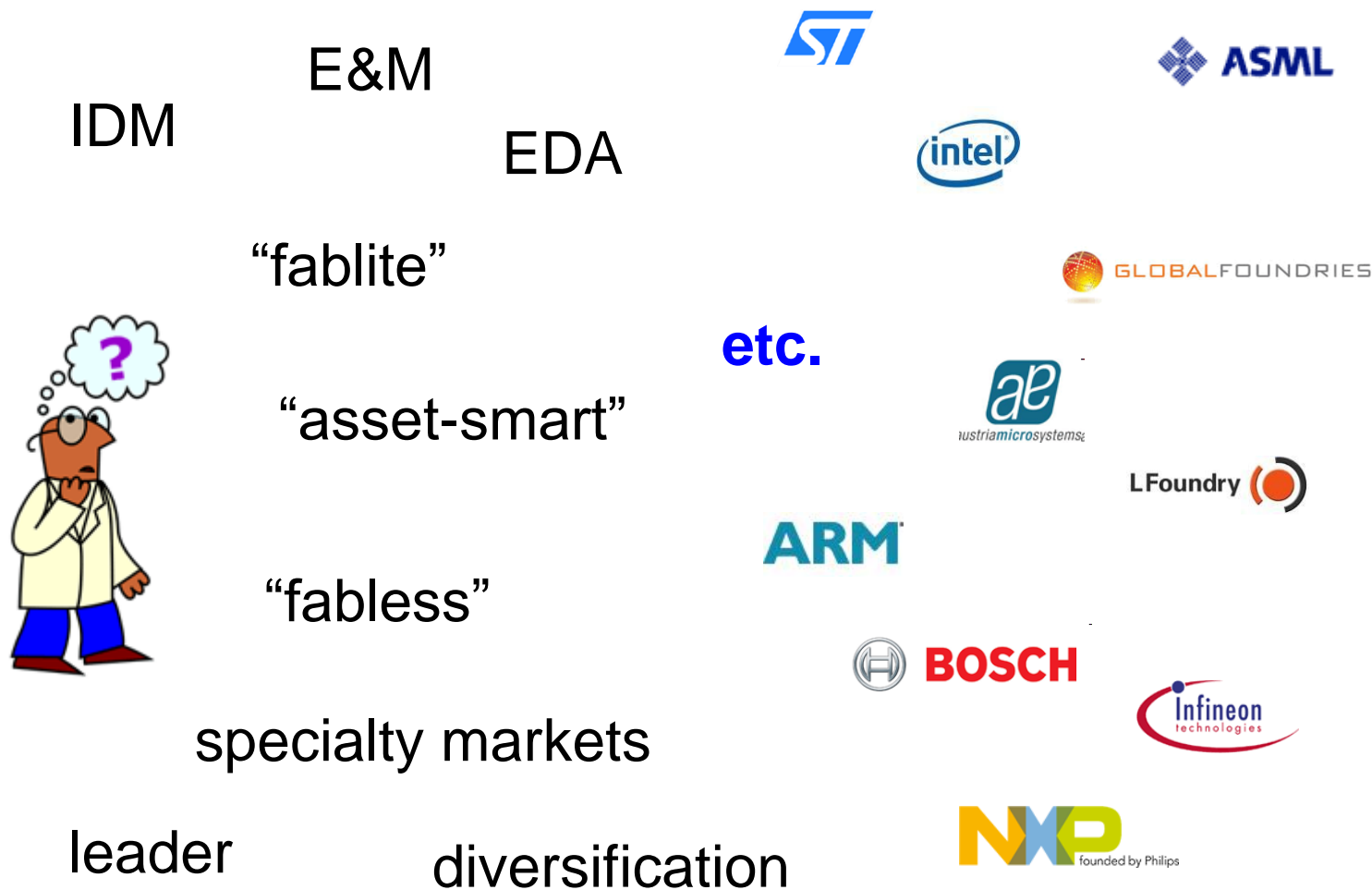
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# Evolution of the technology landscape





# What future for the European “More Moore”?



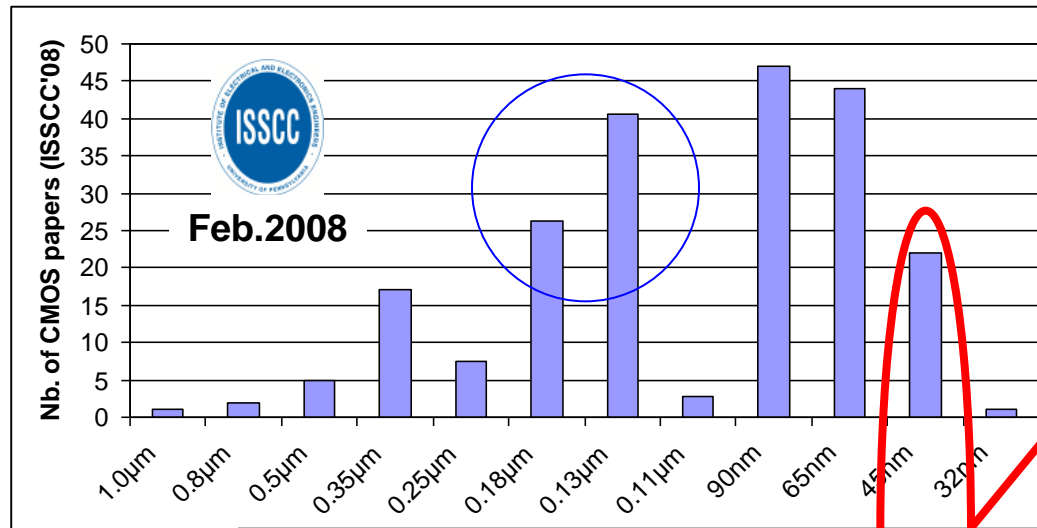
## 3D integration

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# Design – technology interaction

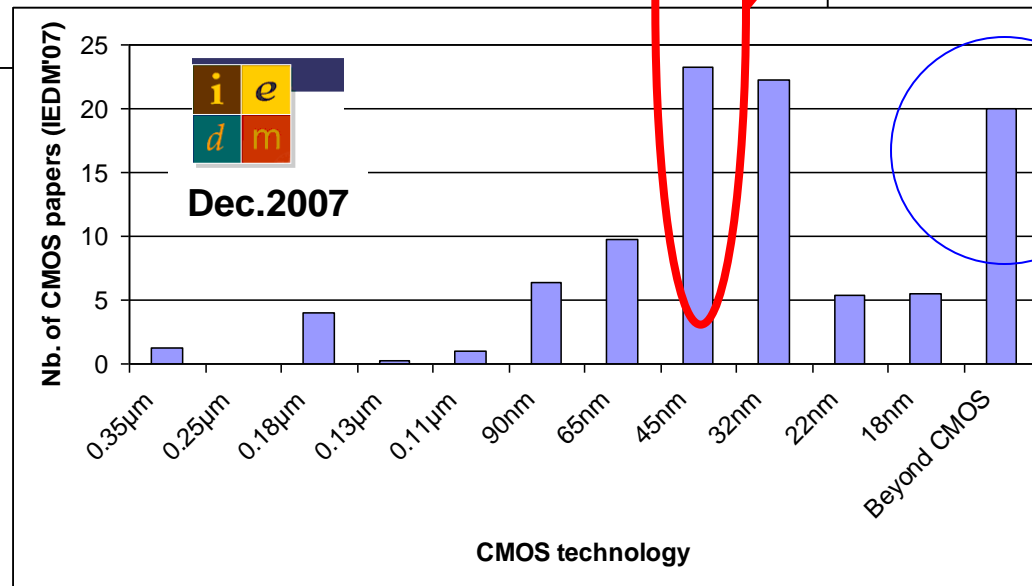
Wishful thinking or real need?

# What drives researchers?



**45nm 'node'**

- variability (?)
- SRAM
- NVM



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# What is new?

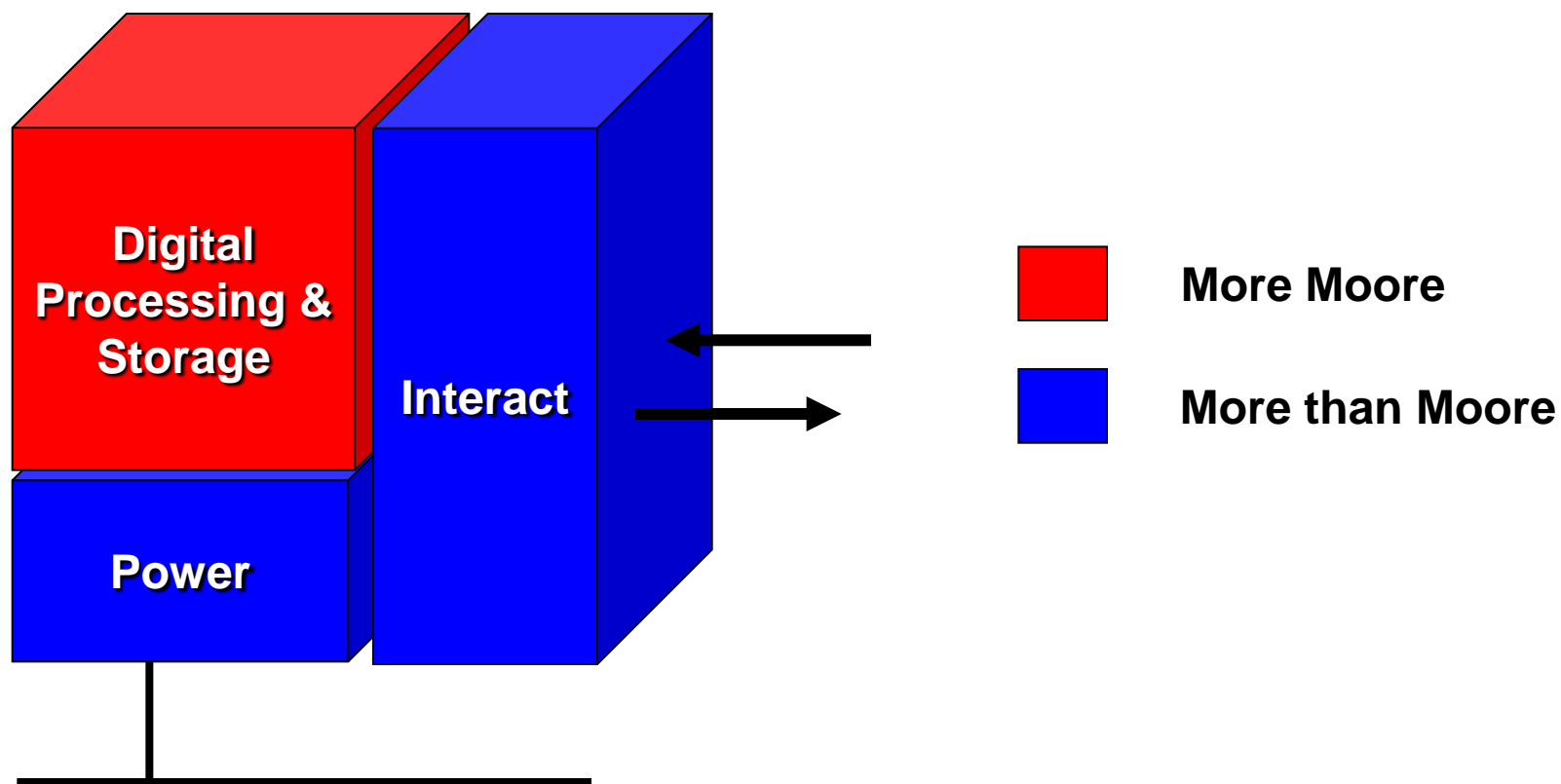
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- Circuits are more sensitive to technology characteristics (e.g. SRAM)
  - C:OS integration development is left to a few IDMs (Intel...) & Alliances (IBM..)
  - The foundry – fabless model is dominating the minds
  - Major fabless companies (Qualcomm...)
    - need to know in advance the details of future technologies
    - intend to drive the technology
- ⇒ design – technology interaction is a must
- ⇒ the way it will happen is not settled

# “More-than-Moore”

The next frontier?

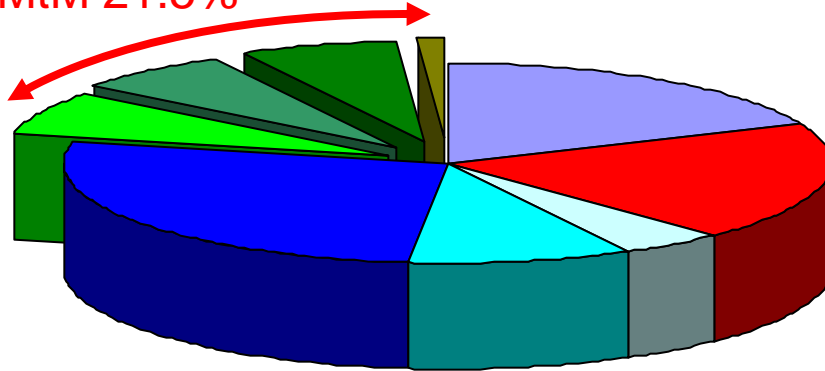
# What is More-than-Moore?





# MM vs. MtM markets

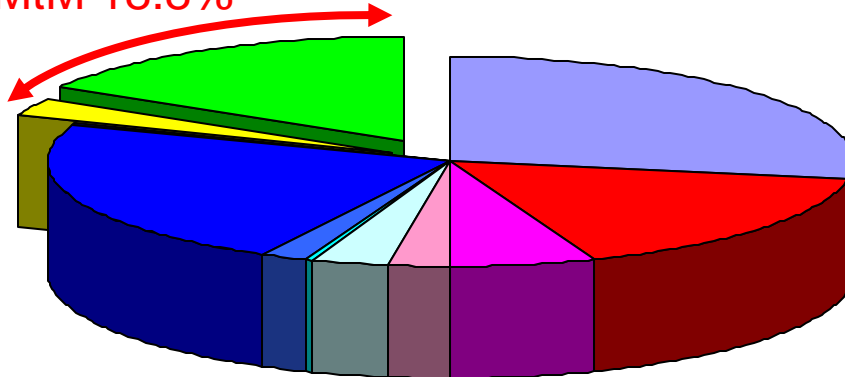
MtM 21.5%



2008  
\$255B market

Source: Gartner Dataquest (03-2009)

MtM 18.8%

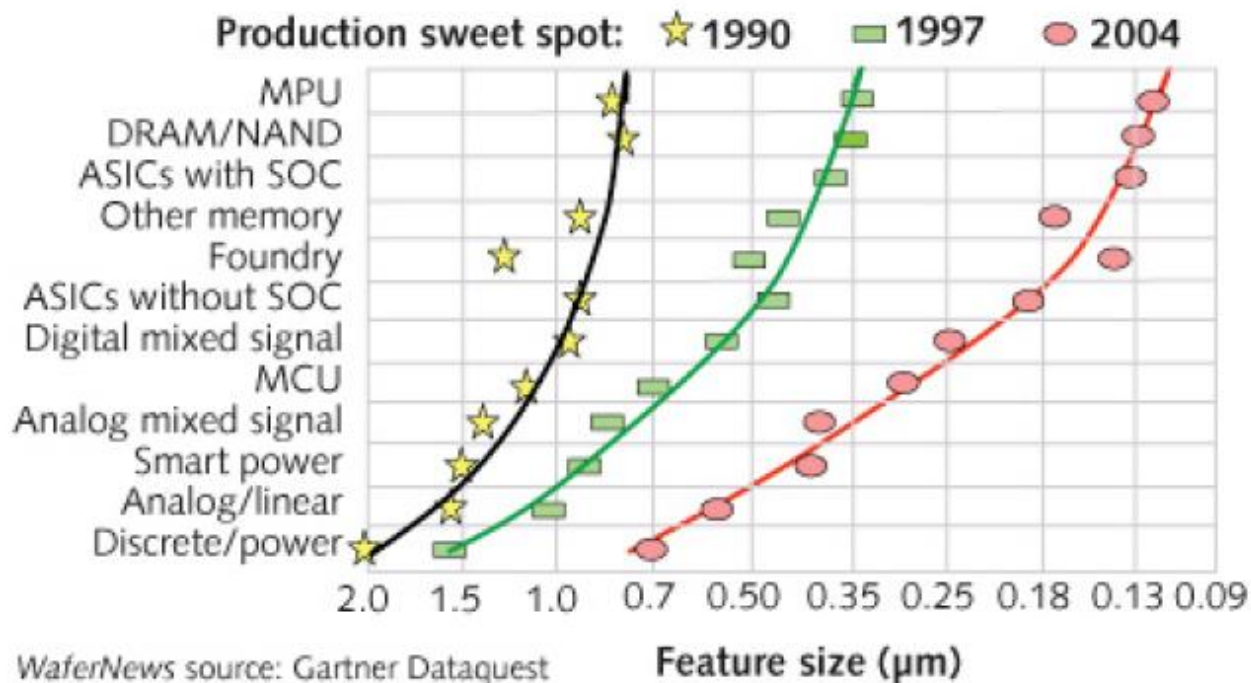


Forecast 2010  
\$244B market

Source: IBS (Q2/2010)

# More-than-Moore dimensions are lagging

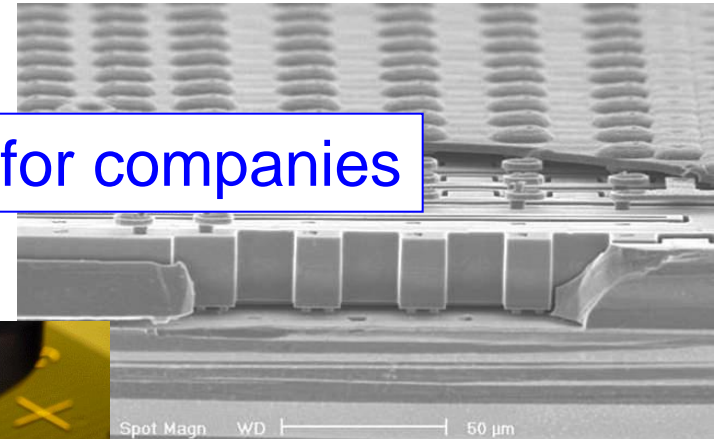
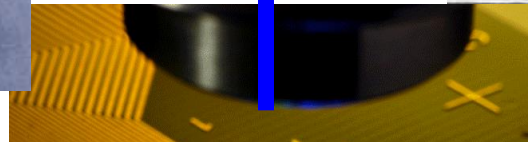
Manufacturing nodes by device, over time



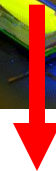
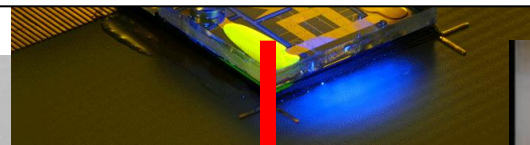
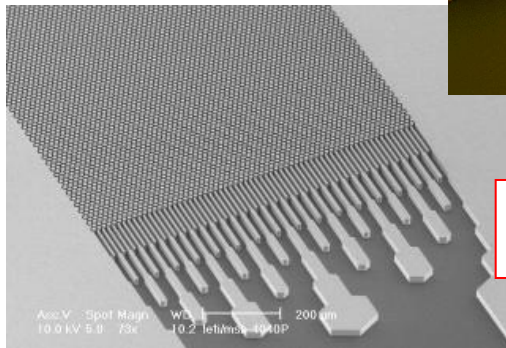
# A wide diversity of new products



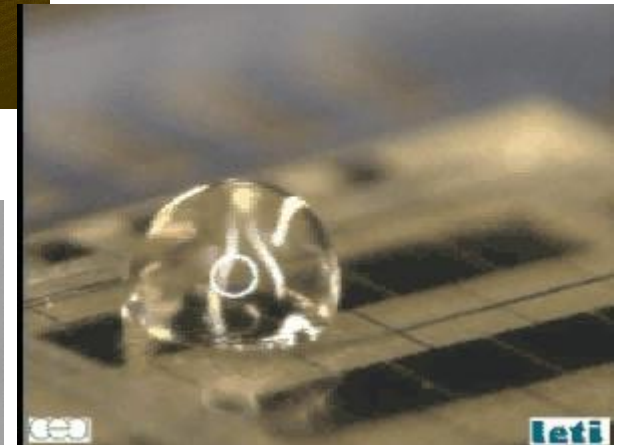
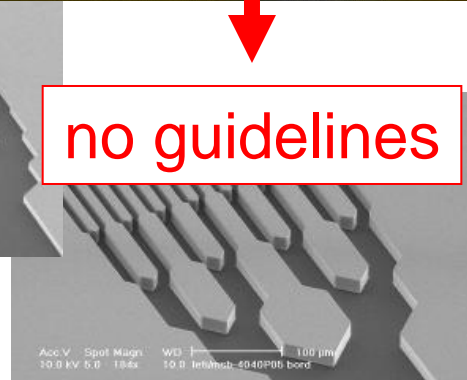
opportunities in R&D and for companies



no established “CMOS-like” legacy process / device



no guidelines



# Economics of differentiated products

~~1 product = 1 process~~

1 product = 1 process variation

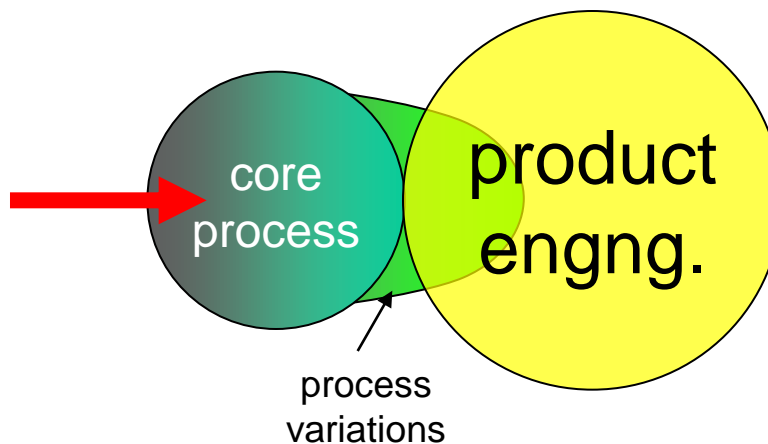


- [mostly] low volume / product or process
- high NRE / product (design, test...)
- high entry barrier (system knowledge)
- process control & yield difficult



- added value → process optimization
- long-lived products

need for  
roadmaps  
/ standards



after P. Pflüger, IEF 2009

Jan. 20, 2011

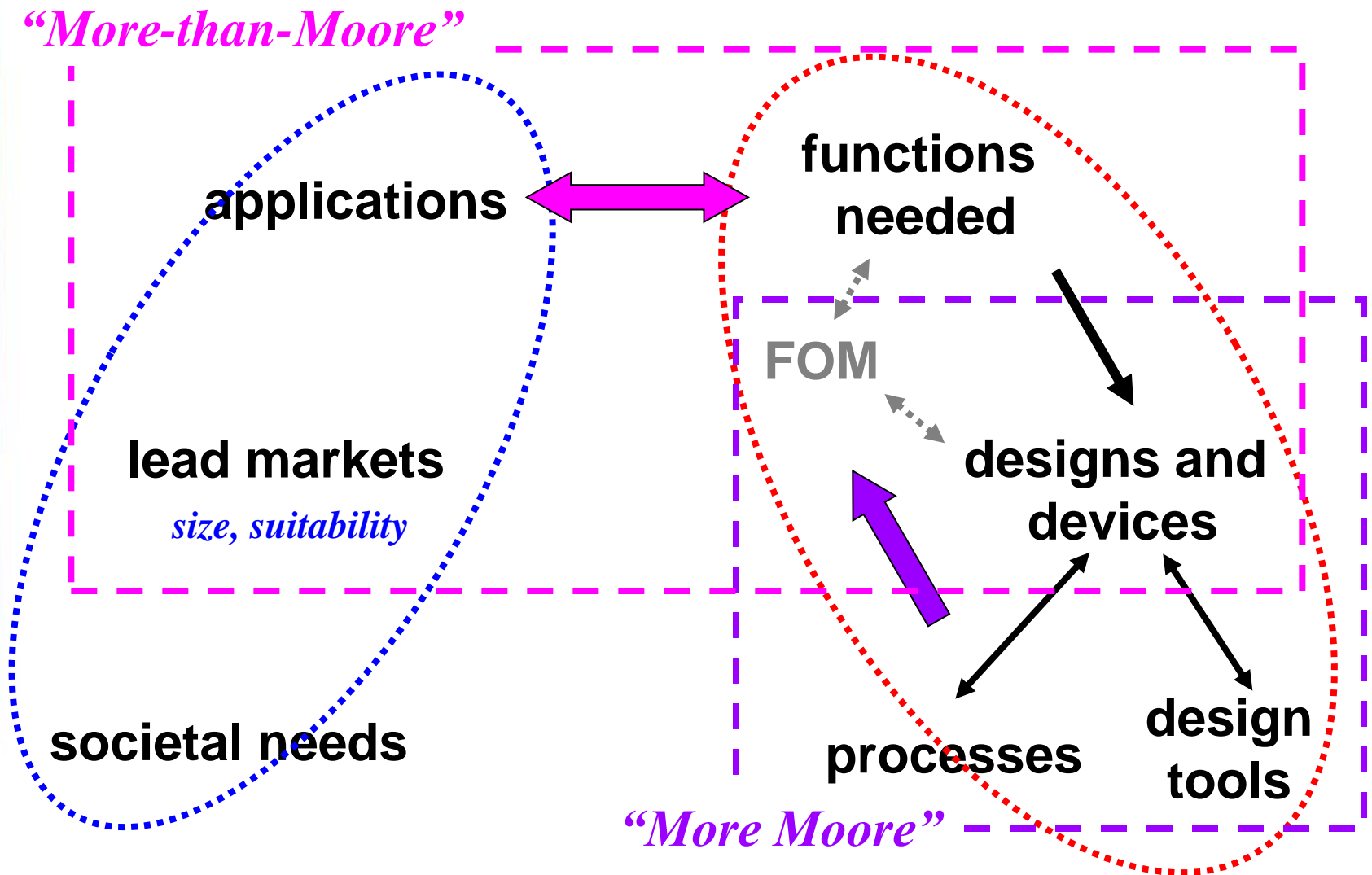
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# Roadmapping?

- preconditions
  - FOM = Figure Of Merit
  - LEP = Law of Expected Progress
  - WAT = Wide Applicability of Technology
  - ECO = Existing COmmunity
  - SHR = Willingness to SHaRe information
- effort started:
  - in ITRS (White Paper) + iNEMI
  - in the CATRENE Scientific Committee

There will not be an exhaustive roadmap for the MtM domain

# Application – Function – Technology interplay





# Conclusion

# Be modest in predicting potential futures

*“Prediction is always difficult, above all of the future.”*

Niels Bohr



*“Heavier-than-air flying machines are impossible”*

Lord Kelvin, president, Royal Society, 1890-1895



*“This 'telephone' has too many shortcomings to be seriously considered as a means of communication.”*

Western Union memo, 1876

*“That is the biggest fool thing we have ever done [research on]... The bomb will never go off. I speak as an expert in explosives.”*

Admiral William D. Leahy, U.S. Atomic Bomb Project, 1944



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# Don't be too **pessimistic** about microelectronics

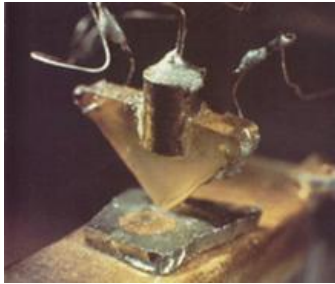
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“The rumors of my death have been greatly exaggerated”

Mark Twain (1897)



# Don't dream too much, but dream right

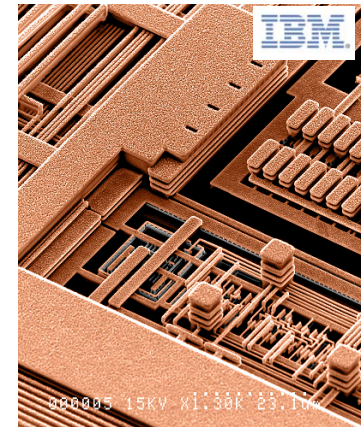


**It is not just a new switch**

**You should never underestimate  
the real complexity  
of building an information processing system**

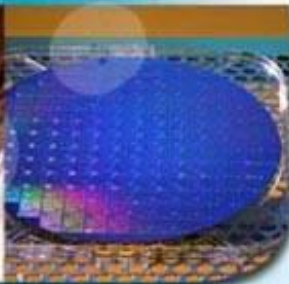
...innovation will arise more and more  
by combining

- materials (physics, chemistry)
- devices
- system (mathematics...)
- and 'soft' sciences



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micro and nanoelectronics  
microsystems  
ambient intelligence  
biology and health  
image chain



# Innovation for industry

Loyalty  
Entrepreneurship  
Team work  
Loyalty  
Entrepreneurship  
Team work  
Innovation

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Energy & Environment

Security

Photonics & Multimedia

Space

Biology & Healthcare

Wireless & Smart Devices

13<sup>th</sup>

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June  
27<sup>th</sup>  
28<sup>th</sup>  
2011

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Innovation for industry

SAVE THE DATE